DMS935E1

Silicon NPN epitaxial planar type (Tr) Silicon epitaxial planar type (CCD load device)

For CCD output circuits

Features

- Two elements incorporated into one package (Tr + CCD load device)
- \bullet High transition frequency f_{T}
- Contributes to miniaturization of sets, reduction of component count.
- Eco-friendly Halogen-free package

Basic Part Number

DSC2G03 + CCD load device (Individual)

Packaging

Embossed type (Thermo-compression sealing): 8000 pcs / reel (standard)

Absolute Maximum Ratings $T_a = 25^{\circ}C$

	Parameter	Symbol	Rating	Unit
Tr1	Collector-base voltage (Emitter open)	V _{CBO}	30	V
	Collector-emitter voltage (Base open)	V _{CEO}	20	V
	Emitter-base voltage (Collector open)	V _{EBO}	3	V
	Collector current	I _C	50	mA
CCD load device	Limiting element voltage	V _{max}	40	V
	Limiting element current	I _{max}	10	mA
Overall	Total power dissipation *	P _T	125	mW
	Junction temperature	Tj	150	°C
	Storage temperature	T _{stg}	-55 to +150	°C

Note) *: Measuring on substrate at $17 \text{ mm} \times 10 \text{ mm} \times 1 \text{ mm}$

Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

• Tr1

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_{\rm C} = 100 \ \mu {\rm A}, I_{\rm E} = 0$	30			V
Emitter-base voltage (Collector open)	V _{EBO}	$I_{\rm E} = 10 \ \mu {\rm A}, I_{\rm C} = 0$	3			V
Base-emitter voltage	V _{BE}	$V_{CE} = 10 \text{ V}, I_C = 2 \text{ mA}$		740		mV
Forward current transfer ratio	h _{FE}	$V_{CE} = 10 \text{ V}, I_C = 2 \text{ mA}$	100		250	
Transition frequency	f _T	$V_{CE} = 10 \text{ V}, I_C = 15 \text{ mA}$		1 300		MHz

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *: Pulse measurement

CCD load device

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Pinchi off current	I _P	$V_{\rm DS} = 10 {\rm V}, {\rm V}_{\rm G} = 0$	3.8		5.2	mA
Output impedance	Zo	$V_{\rm DS} = 10 {\rm V}, {\rm V}_{\rm G} = 0$		0.05		μΩ

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

Package

- Code
- SSMini6-F3-B
- Pin Name

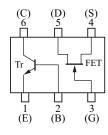
3: Gate

- 1: Emitter 4: Source
- 2: Base
 - 6: Collector

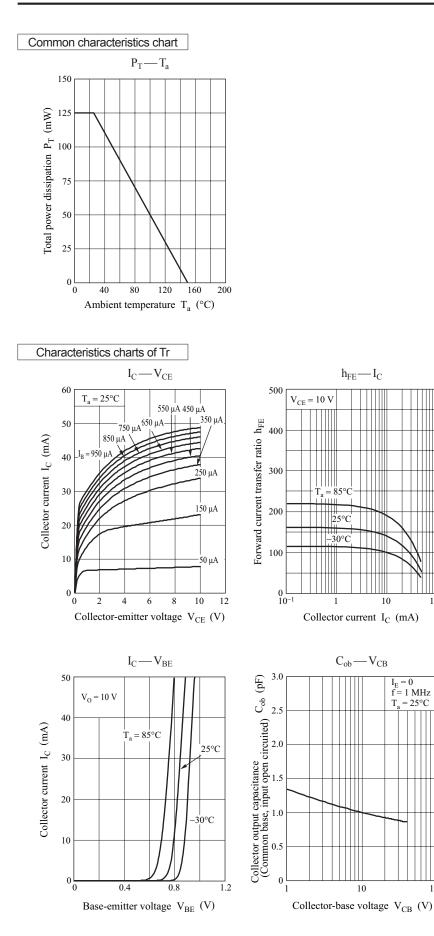
5: Drain

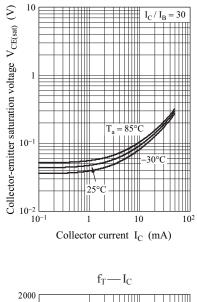
Marking Symbol: X0

Internal Connection



DMS935E1

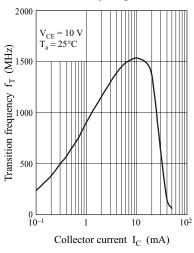




 10^{2}

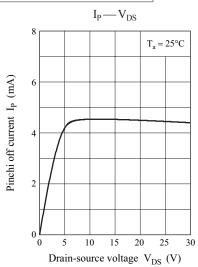
100

V_{CE(sat)}-I_C



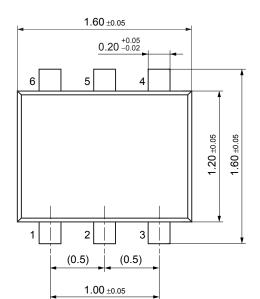
Panasonic

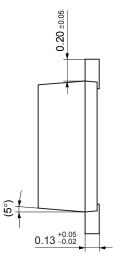
Characteristics charts of CCD

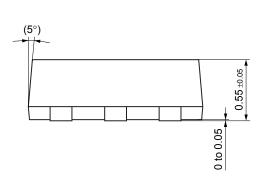


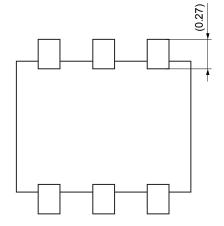
SSMini6-F3-B

Unit: mm









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